

N-Channel 60 V (D-S) MOSFET

PRODUCT SUMMARY					
V _{DS} (V)	R _{DS(on)} (Ω)	I _D (A) ^a			
60	0.024 at V _{GS} = 10 V	50			
00	0.028 at V _{GS} = 4.5 V	40			

FEATURES

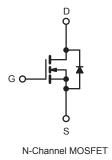
- Halogen-free According to IEC 61249-2-21 Definition
- Surface Mount
- Available in Tape and Reel
- Dynamic dV/dt Rating
- Logic-Level Gate Drive
- Fast Switching
- Compliant to RoHS Directive 2002/95/EC



Ο GDS

Top View

TO-220AB



ABSOLUTE MAXIMUM RATINGS (T_C	= 25 °C, unl	ess otherwis	se noted)			
PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-Source Voltage			V _{DS}	60	V	
Gate-Source Voltage			V _{GS}	± 20	V V	
Continuous Drain Current ^f	V _{GS} at 10 V	$T_C = 25 \text{ °C}$ $T_C = 100 \text{ °C}$	I-	50		
Continuous Drain Current	VGSALIOV	T _C = 100 °C	ID	36	A	
Pulsed Drain Current ^a			I _{DM}	200		
Linear Derating Factor			-	1.0	W/°C	
Linear Derating Factor (PCB Mount) ^e				0.025	VV/ C	
Single Pulse Avalanche Energy ^b			E _{AS}	400	mJ	
Maximum Power Dissipation T _C = 25 °C			р	150	w	
Maximum Power Dissipation (PCB Mount) ^e	T _A = 25 °C		P _D	3.7	vv	
Peak Diode Recovery dV/dt ^c			dV/dt	4.5	V/ns	
Operating Junction and Storage Temperature Range			T _J , T _{stg}	- 55 to + 175	- °C	
Soldering Recommendations (Peak Temperature) ^d for 10 s			300 ^d			

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b. $V_{DD} = 25 \text{ V}$, starting $T_J = 25 \text{ °C}$, $L = 179 \text{ }\mu\text{H}$, $R_g = 25 \Omega$, $I_{AS} = 51 \text{ A}$ (see fig. 12). c. $I_{SD} \le 51 \text{ A}$, dl/dt $\le 250 \text{ A/}\mu\text{s}$, $V_{DD} \le V_{DS}$, $T_J \le 175 \text{ °C}$.

e. When mounted on 1" square PCB (FR-4 or G-10 material).

f. Current limited by the package, (die current = 51 A).

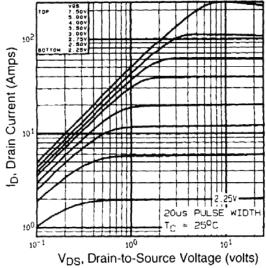
d. 1.6 mm from case.



THERMAL RESISTANCE RATI	NGS							
PARAMETER	SYMBOL	ТҮР		MAX.		UNIT		
Maximum Junction-to-Ambient	R _{thJA}	-		62		1		
Maximum Junction-to-Ambient (PCB Mount) ^a	R _{thJA}	-		40	°C/W			
Maximum Junction-to-Case (Drain)	R _{thJC}	- 1.0						
lote When mounted on 1" square PCB (FR-4	or G-10 material)). 1						
SPECIFICATIONS (T _J = 25 $^{\circ}$ C, U	nless otherwi	ise noted)						
PARAMETER	SYMBOL	TES		IONS	MIN.	TYP.	MAX.	UNIT
Static		•						
Drain-Source Breakdown Voltage	V _{DS}	V _{GS}	= 0, I _D = 25	50 µA	60	-	-	V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Referenc	e to 25 °C,	I _D = 1 mA	-	0.070	-	V/°C
Gate-Source Threshold Voltage	V _{GS(th)}	V _{DS} =	V _{GS} , I _D = 2	250 μΑ	1.0	-	2.5	
Gate-Source Leakage	I _{GSS}		$V_{\rm GS} = \pm 10^{-1}$		-	-	± 100	nA
		$V_{DS} = 60 \text{ V}, \text{ V}_{GS} = 0 \text{ V}$			-	-	25	
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = 48 V,	$V_{GS} = 0 V,$	T _J = 150 °C	_	-	250	μA
		V _{GS} = 10 V		= 21 A ^b	_	0.024	_	Ω
Drain-Source On-State Resistance	R _{DS(on)}	V _{GS} = 4.5 V		= 15 A ^b	_	0.028	_	
Forward Transconductance	g _{fs}		= 25 V, I _D =		23	-	-	S
Dynamic	513	20	, ,					
Input Capacitance	C _{iss}				_	190		
Output Capacitance	C _{oss}		$V_{GS} = 0 V,$ $V_{DS} = 25 V$		_	920	-	pF
Reverse Transfer Capacitance	C _{rss}		0 MHz, see			170	-	
Total Gate Charge					-	170	66	
5	Q _g	$V_{GS} = 5.0 \text{ V} \qquad \begin{array}{c} I_{D} = 51 \text{ A}, V_{DS} = 48 \text{ V},\\ \text{see fig. 6 and } 13^{\text{b}} \end{array}$		_	-	12	nC	
Gate-Source Charge	Q _{gs}			-	-			
Gate-Drain Charge	Q _{gd}						43	
Turn-On Delay Time	t _{d(on)}				-	17	-	ns
Rise Time	t _r		= 30 V, I _D =	51 A, 2, see fig. 10 ^b	-	230	-	
Turn-Off Delay Time	t _{d(off)}	$n_g = 4.0.52$, 1	1D - 0.00 24	2, see lig. 10*	-	2	-	
Fall Time	t _f				-	110	-	
Internal Drain Inductance	L _D	Between lead, 6 mm (0.25") from package and center of die contact		-	4.5	-	nH	
Internal Source Inductance	L _S			-	7.5	-		
Drain-Source Body Diode Characteristic	cs							
Continuous Source-Drain Diode Current	I _S	MOSFET symbol showing the		-	-	50 ^c	A	
Pulsed Diode Forward Current ^a	I _{SM}	p - n junction diode			-	-		200
Body Diode Voltage	V _{SD}	T _J = 25 °C, I _S = 51 A, V _{GS} = 0 V ^b		-	-	2.5	V	
Body Diode Reverse Recovery Time	t _{rr}			-	130	180	ns	
Body Diode Reverse Recovery Charge	Q _{rr}	$T_J = 25 \text{ °C}, I_F = 51 \text{ A}, dl/dt = 100 \text{ A}/\mu\text{s}^{b}$			-	0.84	1.3	μC
Forward Turn-On Time	t _{on}	Intrincio tu	rn on time	is negligible (turn	on is dor	ninated b	vl and	1 -)

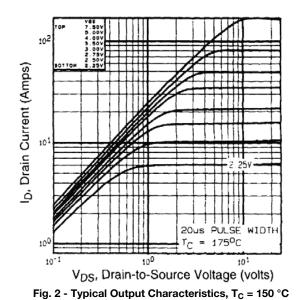
Notes
a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
b. Pulse width ≤ 300 µs; duty cycle ≤ 2 %.
c. Current limited by the package, (Die Current = 51 A).

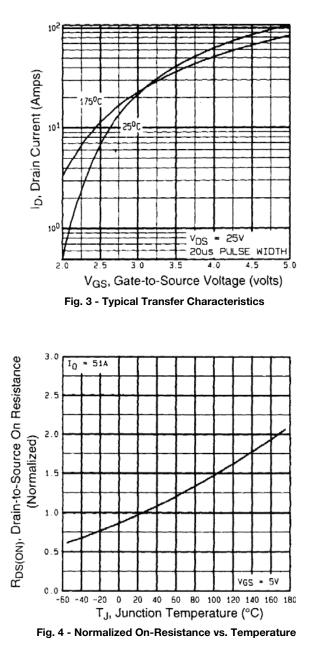




TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)









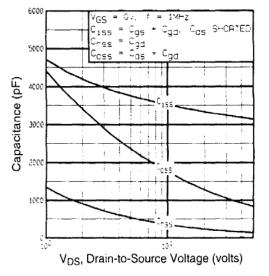


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

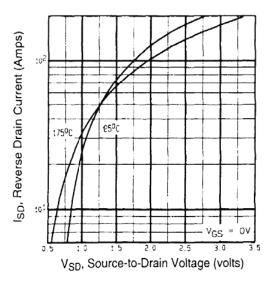
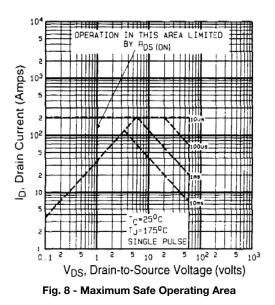


Fig. 7 - Typical Source-Drain Diode Forward Voltage



Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage





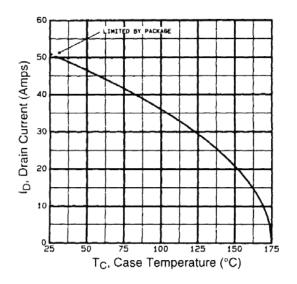


Fig. 9 - Maximum Drain Current vs. Case Temperature

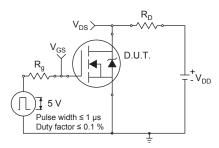


Fig. 10a - Switching Time Test Circuit

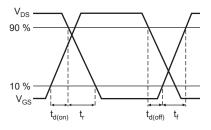


Fig. 10b - Switching Time Waveforms

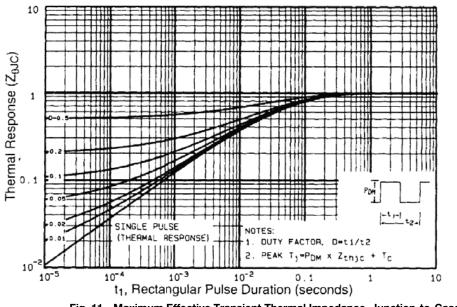


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case



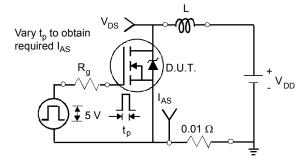


Fig. 12a - Unclamped Inductive Test Circuit

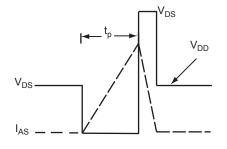


Fig. 12b - Unclamped Inductive Waveforms



Fig. 12c - Maximum Avalanche Energy vs. Drain Current

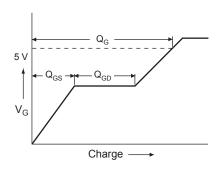


Fig. 13a - Basic Gate Charge Waveform

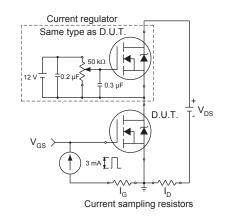
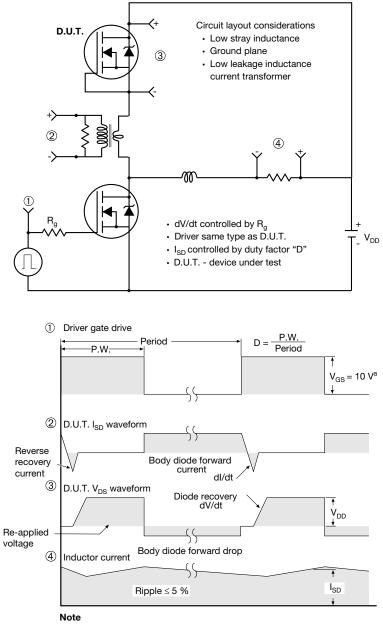


Fig. 13b - Gate Charge Test Circuit



Peak Diode Recovery dV/dt Test Circuit

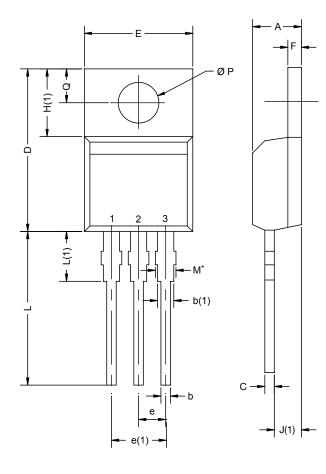


a. V_{GS} = 5 V for logic level devices

Fig. 14 - For N-Channel



TO-220AB



	MILLIN	IETERS	INC	HES
DIM.	MIN.	MAX.	MIN.	MAX.
А	4.25	4.65	0.167	0.183
b	0.69	1.01	0.027	0.040
b(1)	1.20	1.73	0.047	0.068
С	0.36	0.61	0.014	0.024
D	14.85	15.49	0.585	0.610
Е	10.04	10.51	0.395	0.414
е	2.41	2.67	0.095	0.105
e(1)	4.88	5.28	0.192	0.208
F	1.14	1.40	0.045	0.055
H(1)	6.09	6.48	0.240	0.255
J(1)	2.41	2.92	0.095	0.115
L	13.35	14.02	0.526	0.552
L(1)	3.32	3.82	0.131	0.150
ØР	3.54	3.94	0.139	0.155
Q	2.60	3.00	0.102	0.118
ECN: X12- DWG: 547	0208-Rev. N, 1	08-Oct-12		

Notes

* M = 1.32 mm to 1.62 mm (dimension including protrusion) Heatsink hole for HVM



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